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IN THE U.S. PATENT AND TRADEMARK OFFICE

August 31, 2005

Applicants Takaomi NAKAYAMA et al

TREATING SOLUTION FOR SURFACE TREATMENT OF For

METAL AND A METHOD FOR SURFACE TREATMENT

PCT International Application No.: PCT/JP2003/015868

PCT International Filing Date: December 11, 2003

U.S. Application No.

(if known, see 37 CFR 1.5): 10/537 329

Atty. Docket No.: 4626.P0002US

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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is Form PTO-1449 and the references cited thereon. These references are mentioned in Applicants' specification. Further comment at this point in time should not be necessary.

JP 8-176841 corresponds to WO 96/19595. JP 9-25436 corresponds to EP 0 838 537. JP 9-31404 corresponds to U.S. 6 059 896. JP 2000-199077 corresponds to U.S. 6 361 833. JP 5-195244 corresponds to U.S. 5 449 414. WO 02/103080 corresponds to U.S. 2004/0244874.

Since this application was filed after June 30, 2003, Applicants hereby accept the USPTO waiver of the requirement under 37 CFR 1.98(a)(2)(i) for submitting a copy of each cited U.S. patent [1273 Off. Gaz. Pat. Off. 55, 8/05/2003].



Further consideration is respectfully solicited.

Respectfully submitted,

Terryence F. Chapman

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INFORMATION DISCLOSURE CITACION

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10/537 329

Filed: June 1, 2005

Conf. No.: Unknown Group: Unknown

Atty. Docket No.: 4626.P0002US

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U.S. PATENT DOCUMENTS

\30	וע	U.S. PATENT DOCUMENTS		
Examer	Cite*/	Document Number -	Publication Date	Name of Patentee or
Init 21s*	No.	Kind Code	MM-DD-YYYY	Applicant
RADE	Cit No.	4 273 592	06-16-1981	KELLY
	AB	4 313 769	02-02-1982	FRELIN et al
	AC	5 380 374	01-10-1995	TOMLINSON
	AD	5 449 414	09-12-1995	DOLAN
	AE	6 059 896	05-09-2000	EHARA et al
	AF	6 361 833 B1	03-26-2002	NAKADA et al
	AG	2004/0244874 A1	12-9-2004	NAKAYAMA et al

FOREIGN PATENT DOCUMENTS

Examiner	Cite	Country Code -	Publication Date		Trans.
Initials*	No.	Document Number -	MM-DD-YYYY	or Applicant	
		Kind Code			
	AI	JP 2000-204485	07-25-2000	SHIMAKURA	X
	AJ	JP 56-136978	10-26-1981	FUJIMOTO et al	Abstract
	AK	JP 8-176841	07-09-1996		
	AL	WO 96/19595	06-27-1996	IINO et al	
	AM	JP 9-25436	01-28-1997		
	AN	EP 0 838 537 A1	04-29-1998	KANDA	
	AO	JP 9-31404	02-04-1997		
	AP	JP 2000-199077	07-18-2000		
	AQ	JP 5 195 244	08-03-1993		
	AR	WO 02/103080 A1	12-27-2002		

NON PATENT LITERATURE DOCUMENTS

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